

TEST REPORT

Applicant: JMTek Industries(Shenzhen) Co., Ltd
Address: 14G, Innovation Tech Building , Quanzhi Science and Technology innovation Park , ShaJing Street , Bao'an District , ShenZhen , China
Equipment Type: Speaker with Wireless Charger
Model Name: BTSW100
Brand Name: N/A
Test Standard: ANSI/IEEE Std 149-1979
Test Date: Oct. 28, 2022
Date of Issue: Nov. 02, 2022

ISSUED BY:

Shenzhen BALUN Technology Co., Ltd.

Tested by: Mai Jintian

Checked by: Tolan Tu

Approved by: Wei Yanquan
(Chief Engineer)

Mai Jintian

Tolan Tu

Wei Yanquan

| Revision History | | |
|-------------------------|----------------------|----------------------|
| Version | Issue Date | Revisions |
| <u>Rev. 01</u> | <u>Nov. 02, 2022</u> | <u>Initial Issue</u> |

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1 GENERAL INFORMATION

1.1 Test Laboratory

| | |
|--------------|--|
| Name | Shenzhen BALUN Technology Co., Ltd. |
| Address | Block B, 1/F, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China |
| Phone Number | +86 755 6685 0100 |

1.2 Test Location

| | |
|----------|---|
| Name | Shenzhen BALUN Technology Co., Ltd. |
| Location | <input checked="" type="checkbox"/> Block B, 1/F, Baisha Science and Technology Park, Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P. R. China |
| | <input type="checkbox"/> 1/F, Building B, Ganghongji High-tech Intelligent Industrial Park, No. 1008, Songbai Road, Yangguang Community, Xili Sub-district, Nanshan District, Shenzhen, Guangdong Province, P. R. China |

2 PRODUCT INFORMATION

2.1 Applicant Information

| | |
|-----------|--|
| Applicant | JMTek Industries(Shenzhen) Co., Ltd |
| Address | 14G, Innovation Tech Building , Quanzhi Science and Technology innovation Park , ShaJing Street , Bao'an District , ShenZhen , China |

2.2 Manufacturer Information

| | |
|--------------|--|
| Manufacturer | JMTek Industries(Shenzhen) Co., Ltd |
| Address | 14G, Innovation Tech Building , Quanzhi Science and Technology innovation Park , ShaJing Street , Bao'an District , ShenZhen , China |

2.3 General Description for Equipment under Test (EUT)

| | |
|-----------------------|-------------------------------|
| EUT Name | Speaker with Wireless Charger |
| Model Name Under Test | BTSW100 |
| Antenna Type | PCB Antenna |
| Dimensions | 14*5mm |

2.4 Ancillary Equipment

Note: Not applicable.

2.5 Technical Information

| | |
|------------------|--|
| Test Frequencies | 2400MHz, 2410MHz, 2420MHz, 2430MHz, 2440MHz, 2450MHz, 2460MHz, 2470MHz, 2480MHz, 2490MHz, 2500MHz. |
|------------------|--|

3 SUMMARY OF TEST RESULTS

3.1 Test Standards

| No. | Identity | Document Title |
|-----|------------------------|--|
| 1 | ANSI/IEEE Std 149-1979 | IEEE Standard Test Procedures for Antennas |

3.2 Test Verdict

| Report Section | Description | Remark |
|----------------|---------------------|--------|
| ANNEX A.1 | Gain and Efficiency | -- |
| ANNEX B | Radiation Pattern | -- |

3.3 Test Uncertainty

The uncertainty is calculated using the methods suggested in the "Guide to the Expression of Uncertainty in Measurement" (GUM) published by ISO.

| Item | Uncertainty |
|------|---------------------|
| Gain | $\pm 1.92\text{dB}$ |

4 GENERAL TEST CONFIGURATIONS

4.1 Test Condition

| Environment Parameter | Selected Values During Tests | | | |
|---|------------------------------|-----------------|---------|-----------------------|
| | Ambient Pressure(KPa) | Temperature(°C) | Voltage | Relative Humidity (%) |
| Normal Temperature, Normal Voltage (NTNV) | 101 | 25 | N/A | 50 |

4.2 Test Equipment List

| Description | Manufacturer | Model | Serial No. | Cal. Date | Cal. Due |
|---|--------------|--------|--------------|------------|------------|
| SG24 Multi-probe Antenna Measurement System | SATIMO | SG24-L | 1101855-0001 | 2021.11.12 | 2024.11.11 |
| Vector Network Analyzer | Agilent | E5071B | MY42404001 | 2022.04.02 | 2023.04.01 |
| Description | Manufacturer | Name | | Version | |
| Test Software | MVG | SPM | | V 1.8 | |

4.3 Test Setup

4.3.1 Antenna gain, efficiency and radiation pattern test setup



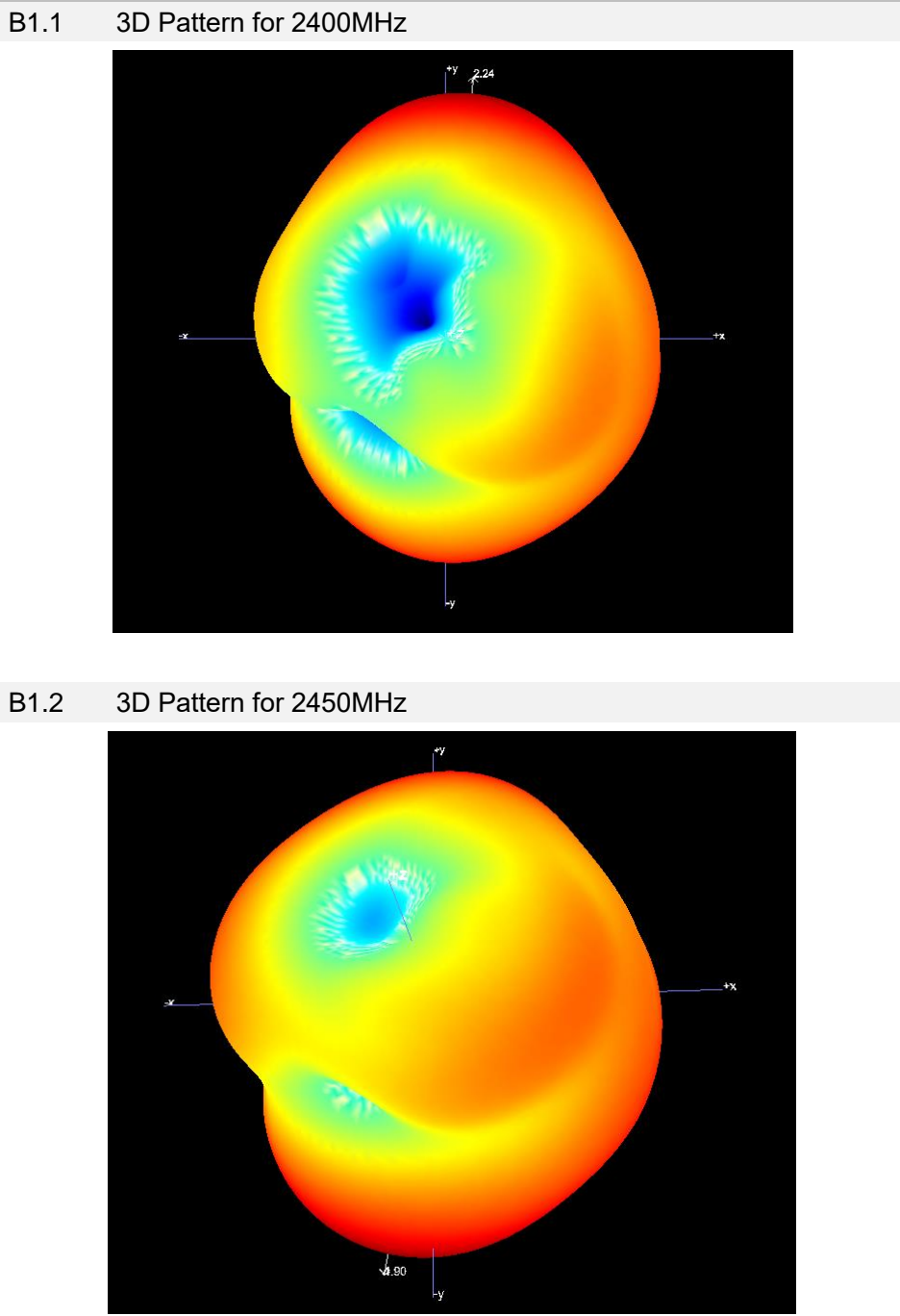
ANNEX A TEST RESULTS

A.1 Gain and Efficiency

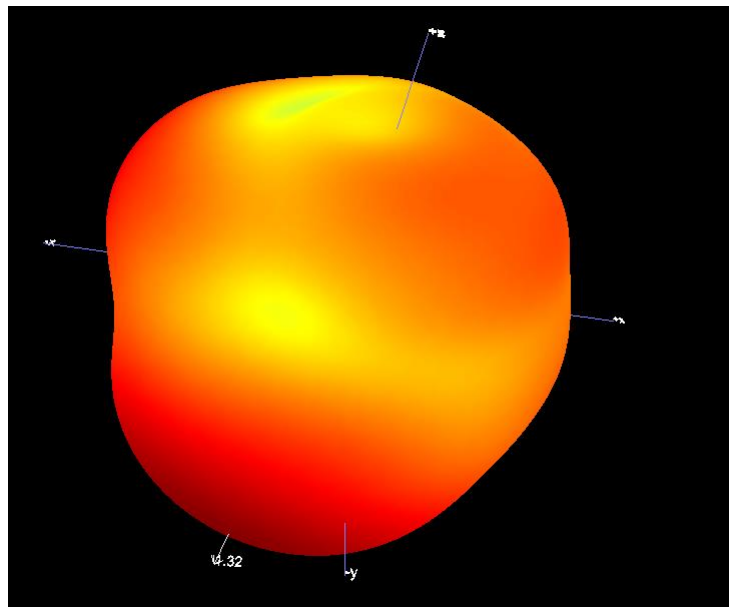
| Frequency | Gain (dBi) | Efficiency (%) |
|-----------|-------------|----------------|
| 2400MHz | 2.24 | 61% |
| 2410MHz | 2.13 | 60% |
| 2420MHz | 1.92 | 58% |
| 2430MHz | 2.18 | 59% |
| 2440MHz | 2.08 | 59% |
| 2450MHz | 1.90 | 58% |
| 2460MHz | 1.69 | 55% |
| 2470MHz | 1.68 | 53% |
| 2480MHz | 1.85 | 53% |
| 2490MHz | 1.71 | 51% |
| 2500MHz | 1.32 | 48% |

ANNEX B RADIATION PATTERN

B.1 3D Pattern

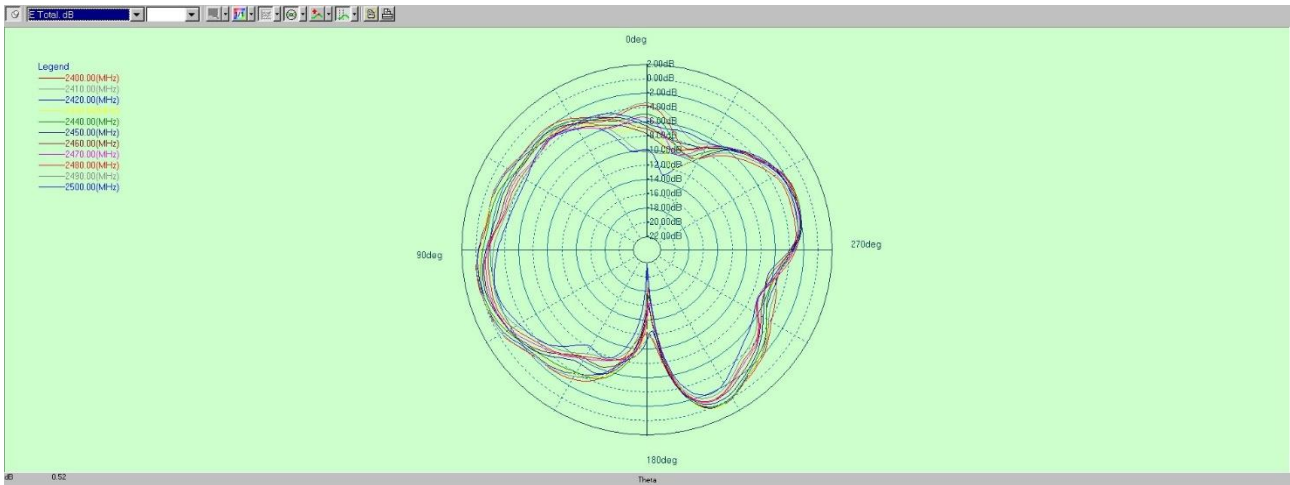


B1.3 3D Pattern for 2500MHz

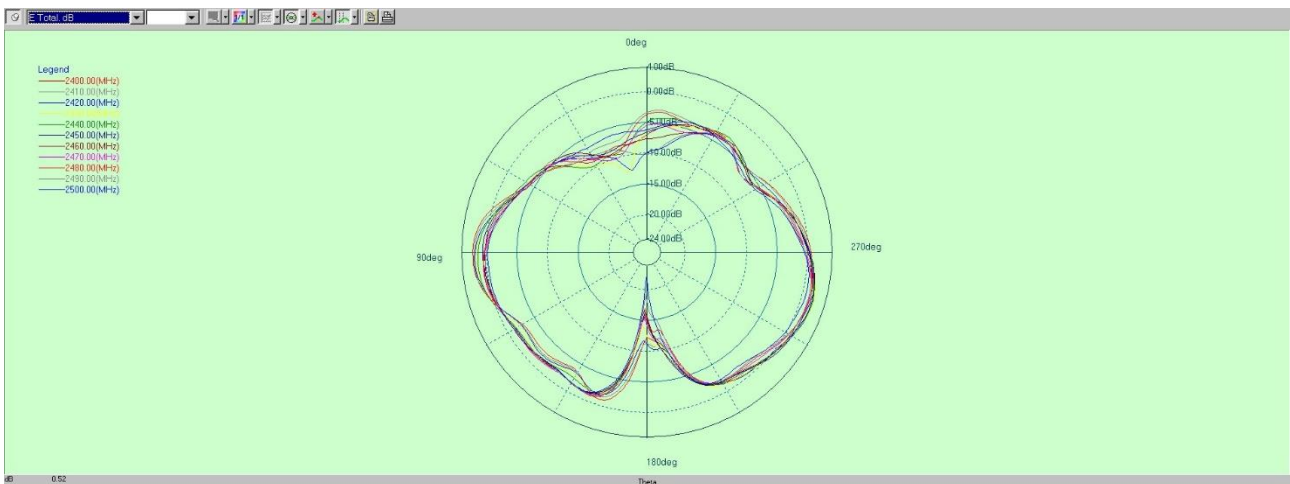


B.2 1D Radiation Pattern

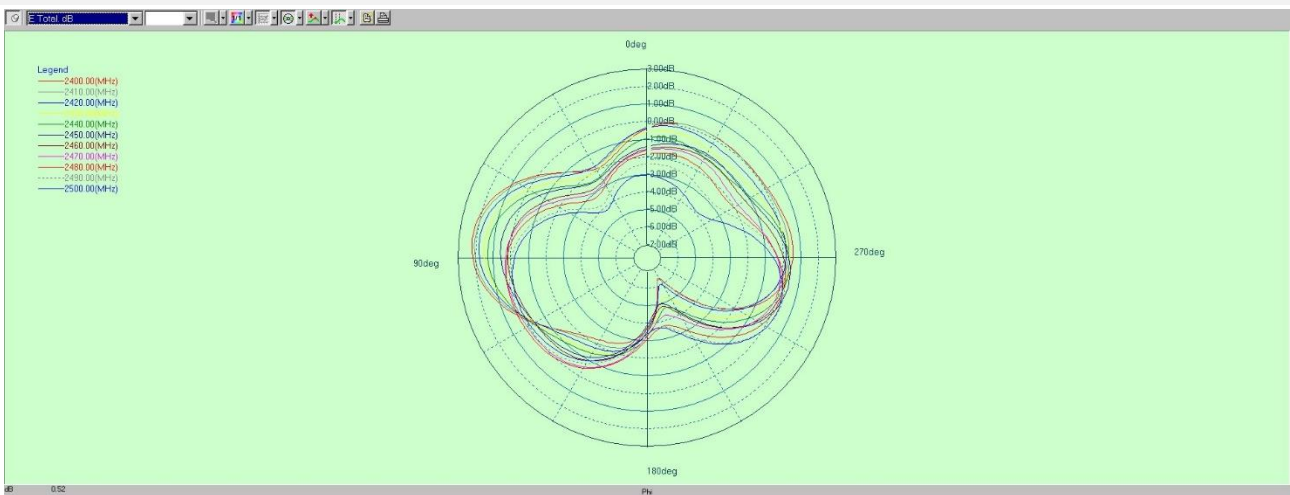
B2.1 PHI=0



B2.2 PHI=90



B2.3 THETA=90



ANNEX C TEST SETUP PHOTOS

Please refer the document “BL-SZ22A0909-AO.PDF”.

ANNEX D EUT PHOTO

Please refer the document “BL-SZ22A0909-AA.PDF”.

Statement

1. The laboratory guarantees the scientificity, accuracy and impartiality of the test, and is responsible for all the information in the report, except the information provided by the customer. The customer is responsible for the impact of the information provided on the validity of the results.
2. The report without China inspection body and laboratory Mandatory Approval (CMA) mark has no effect of proving to the society.
3. For the report with CNAS mark or A2LA mark, the items marked with "☆" are not within the accredited scope.
4. This report is invalid if it is altered, without the signature of the testing and approval personnel, or without the "inspection and testing dedicated stamp" or test report stamp.
5. The test data and results are only valid for the tested samples provided by the customer.
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7. Any objection shall be raised to the laboratory within 30 days after receiving the report.

--END OF REPORT--